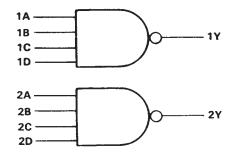
- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

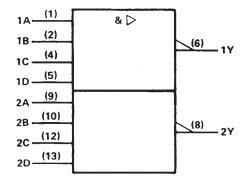
These devices contain two independent 4-input positive-NAND 50-ohm line drivers. They perform the Boolean function $Y = \overline{ABCD}$.

The SN54S140 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74S140 is characterized for operation from 0°C to 70°C.

logic diagram (each driver)



logic symbol†



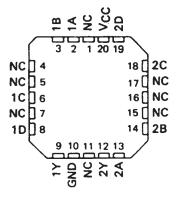
[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN54S140 . . . J OR W PACKAGE SN74S140 . . . D OR N PACKAGE (TOP VIEW)

1A[[U14 VCC
1 B □ 2	13 2D
NC □3	12] 2C
1C ☐ 4	11DNC
1D □ 5	10 2B
1ҮД6	9 🕽 2A
GND 7	8 2Y

SN54S140 . . . FK PACKAGE (TOP VIEW)

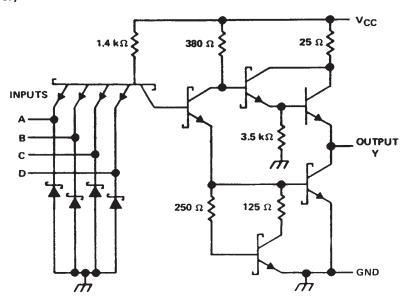


NC-No internal connection



SDLS210 - DECEMBER 1983 - REVISED MARCH 1988

schematic (each driver)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range: SN54'	– 55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	– 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



recommended operating conditions

	:	SN54S140			SN74S140		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH High-level input voltage	2			2			V
VIL Low-level input voltage			0,8			8.0	V
IOH High-level output current			- 40			- 40	mA
IOL Low-level output current			60			60	mA
TA Operating free-air temperature	– 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER TEST		7507 0011P1710119			SN54S140			SN74S140		
		1521 CONDIT	EST CONDITIONS		TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = MIN,	I ₁ = - 18 mA				- 1.2			- 1.2	V
V	V _{CC} = MIN,	VIL = 0.8 V,	I _{OH} = - 3 mA	2.5	3.4		2.7	3,4		V
VOH	V _{CC} = MIN,	VIL = 0.5 V,	$R_O = 50 \Omega$ to GND	2			2			
VOL	V _{CC} = MIN,	V _{1H} = 2 V,	I _{OL} = 60 mA			0.5			0.5	V
l ₁	V _{CC} = MAX,	V ₁ = 5.5 V				1			1	mA
ЧН	V _{CC} = MAX,	V _{IH} = 2.7 V				0.1			0.1	mA
Iις	V _{CC} = MAX,	V _{IL} = 0.5 V				- 4			- 4	mA
los \$	V _{CC} = MAX			- 50		- 225	- 50		- 225	mΑ
¹ ССН	V _{CC} = MAX,	V1 = 0 V			10	18		10	18	mA
¹ CCL	V _{CC} = MAX,	V ₁ = 4.5 V			25	44		25	44	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN TYP	MAX	UNIT	
tPLH			D -03 O	C = 50 = 5	4	6.5	ns
tPHL	0.71	V	R _L = 93 Ω,	C _L = 50 pF	4	6.5	ns
tPLH	Any	'	D -02.0	C _L = 150 pF	6		ns
t _{PHL}			R _L = 93 Ω,		6		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{C}$.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed 100 milliseconds.

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